Amendments to the Specification:

Please replace the abstract with the following abstract:

A circuit has a first memory for modifiable storage of information, the information being modifiable by an ambient parameter of the circuit, which ambient parameter acts on the first memory. The first memory includes a test memory area for storing test information. The circuit also includes a second memory for unmodifiable storage of reference information and a detection circuit. The test information and reference information is supplied to the detection circuit. The detection circuit then detects whether a modification of the originally stored test information has been brought about by an ambient parameter acting on the first memory.

Please replace paragraph [0011] with the following amended paragraph:

[0011] In the case of a solution according to the invention, it has also proven advantageous to include an enabling circuit for the purpose of irreversibly enabling functioning of the detection circuit~~for the features as claimed in claim 3 or claim 8 to be provided~~. In this way, the advantage is achieved that, during a testing state time period, as provided for example during or after production of the circuit, functioning of the detection means may be prevented. In addition, the advantage is achieved that functioning of the detection means may be started at a well-defined time and that this functioning of the detection means can no longer be cancelled once started, whereby, from this time onwards, any modification of the information stored in the first memory means brought about by an ambient parameter for whatever reason may be reliably detected.

Please replace paragraph [0012] with the following amended paragraph:

[0012] In the case of a solution according to the invention, it has also proven advantageous to generate and output an indicator signal to indicate a modification of the originally stored test information brought about by an ambient parameter acting on the first memory~~for the features as claimed in claim 4 or claim 9 to be provided~~. In this way, the advantage is achieved that, after detection of a modification of the test

information brought about by the ambient parameter acting on the first memory means, operating behavior may be influenced to the effect that any criminally motivated use of the circuit or of the data carrier is reliably prevented.

Please replace paragraph [0013] with the following amended paragraph:

[0013] In the case of a solution according to the invention, it has also proven advantageous to form the test information of at least two bits that differ from one another with regard to their logical value~~for the features as claimed in claim 5 or claim 10 to be provided~~. In this way, the advantage is achieved that the test information is represented by a bit sequence which comprises only bits with logical values which do not occur during production of the first memory means or are not present after a modification of the information stored in the first memory means brought about by the action of an ambient parameter on the first memory means, wherein it may be mentioned, for the sake of completeness, that in both cases each bit of the first memory means represents either a logical one or a logical zero.

Please replace paragraph [0014] with the following amended paragraph:

[0014] In the case of a solution according to the invention, it has also proven advantageous to provide the circuit in the form of an integrated circuit~~for the features as claimed in claim 11 to be provided~~. In this way, the advantage is achieved that the circuit may be produced as economically as possible on a large scale.

Please replace paragraph [0033] with the following amended paragraph:

[0033] In the data structure of the first memory means 5, illustrated in FIG. 3, the test memory area 7 from Figs. 1 and 2 is distributed over each of the data sectors within user memory area 6, such that each data sector has its "own" test information TI assigned to it, which is represented by a test information bit pair BP, BPA and BPB respectively, the first three data sectors 8, 9 and 10 being illustrated as representatives of the large number of data sectors. In each sector access control byte 11, 11A and 11B, two bits are reserved for the test information TI, TIA and TIB respectively assigned to the respective data sector 8, 9 and 10. In this way, the advantage is

achieved that, even if the ambient parameter acts in isolated manner on one zone of the first memory means 5, a modification of the originally stored test information TI, TIA or TIB respectively brought about by an ambient parameter acting on the first memory means 5 may be detected virtually one hundred percent reliably. However, it should be mentioned at this point that more than two bits may be provided within each data sector 8, 9 and 10 to represent the respective test information TI, TIA and TIB respectively and that the individual bits do not have to be arranged next to one another.